Search Notes					

Applicant(s)/Patent under Reexamination

10/517,893

KOUTONEN ET AL.
Art Unit

Examiner

SANG KIM

3654

SEARCHED				
Class	Subclass	Date	Examiner	
242	534 541 542	3/18/2007	SK	
242	542.2	3/18/2007	SK	
242	542.4	3/18/2007	SK	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
John Nguyen: 242/541, 542	3/18/2007	SK
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